

15 V, 8 A, HIGH PERFORMANCE HALF BRIDGE

Features

- ZqFET™ High Performance Technology
- Supports Switching Frequencies up to 2 MHz
- $R_{DS(ON)4.5V}$ of 20 / 8 mΩ (Q1 / Q2)
- Extremely Low Gate Charge and Output Capacitance for Low Switching Losses
- QFN 3.7 mm x 4 mm Thermally Enhanced Package

Applications

- Small, Efficient DC/DC Converters
- Battery Powered Electronics
- Power Blocks for Buck or Buck-Boost Converters

Product Description

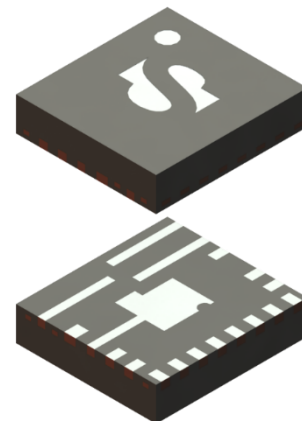
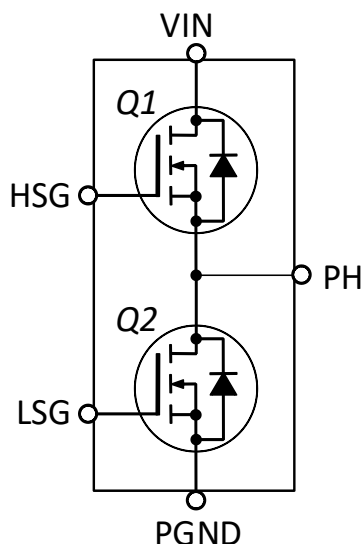
The SZPB9317A-B is a compact, high efficiency half bridge optimized for high frequency applications. It contains Silanna's proprietary ZqFET™ in a half bridge configuration, capable of delivering 8 A of output current with a wide range of inputs up to 15 V.

Silanna's proprietary ZqFET™ technology offers industry's benchmark performance that reduces both switching and conduction losses for operation at switching frequencies up to 2 MHz.

The SZPB9317A-B has been optimally designed for operation as a half bridge for high frequency DC/DC buck converters. The device is fabricated in a standard silicon process. The ZqFET™ structure provides for extremely low, world class switching losses for a given on resistance rivalling devices fabricated in exotic processes.

The SZPB9317A-B is available in a space-saving and thermally enhanced QFN 3.7 mm x 4 mm package.

Device Overview



WARNING: These devices have limited built-in ESD protection. The leads should be shorted together with the device placed in conductive containers during storage or handling to prevent electrostatic damage to the Power ZqFET®'s MOS gates.

Contents

| | |
|--|----|
| Features | 1 |
| Applications | 1 |
| Product Description | 1 |
| Pin Descriptions | 3 |
| Pin Definitions | 3 |
| Internal Block Diagram | 4 |
| Absolute Maximum Ratings..... | 4 |
| Thermal Information | 5 |
| Recommended Operating Conditions | 5 |
| Static Electrical Characteristics | 6 |
| Dynamic Electrical Characteristics | 7 |
| Product Ordering Information | 8 |
| Product Image | 8 |
| Package Dimensions..... | 9 |
| Recommended PCB Footprint | 10 |
| Revision History | 11 |

Figures

| | |
|---|----|
| Figure 1: Top Transparent View | 3 |
| Figure 2: Internal Block Diagram | 4 |
| Figure 3: SZPB9317A-B Product Image..... | 8 |
| Figure 4: F34 Package Dimensions | 9 |
| Figure 5: Recommended PCB Footprint | 10 |

Pin Descriptions

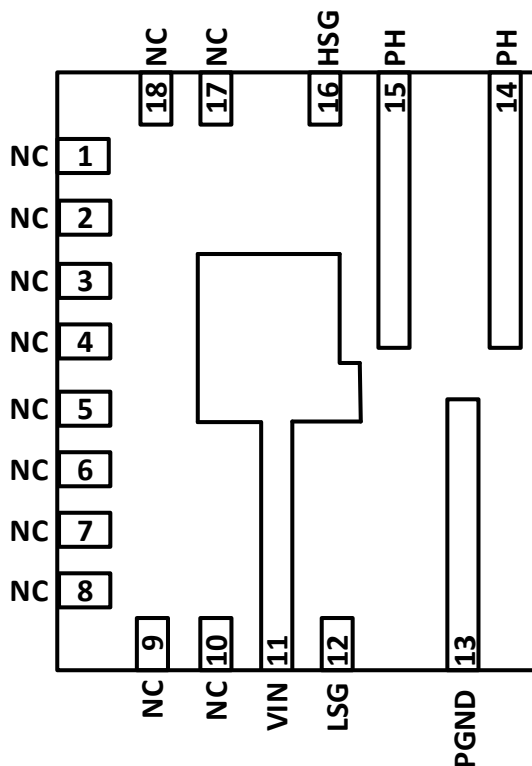


Figure 1: Top Transparent View

Pin Definitions

| Pin # | Name | Description |
|-------|------|--|
| 1-10 | NC | No connect. May be used to connect to a large PCB pad area of VIN. |
| 11 | VIN | Input voltage to Power Block, drain of Q1. |
| 12 | LSG | Input connection to the gate of the low-side FET, Q2. |
| 13 | PGND | Power ground connection to the source of the low-side FET, Q2. |
| 14-15 | PH | Connections to the phase node of the half bridge, drain of low-side FET and source of the high-side FET. |
| 16 | HSG | Input connection to the gate of the high-side FET, Q1. |
| 17-18 | NC | No connect. May be used to connect to a large PCB pad area of VIN. |

Internal Block Diagram

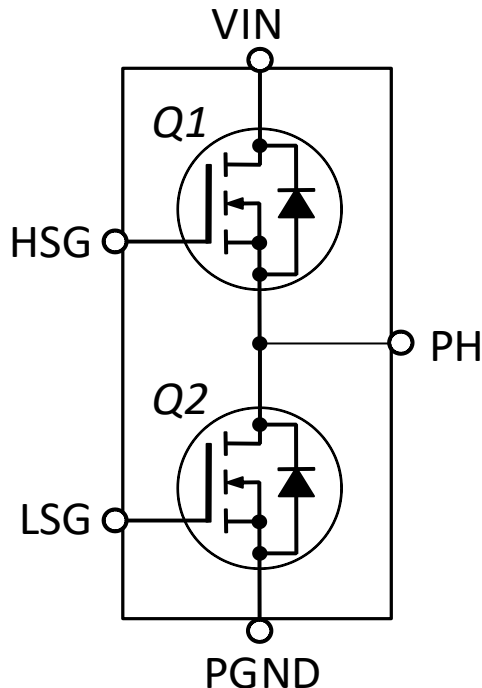


Figure 2: Internal Block Diagram

Absolute Maximum Ratings ^{Note 1}

($T_a = 25^\circ\text{C}$ Unless Otherwise Specified, relative to PGND.)

| Parameter | Symbol | Device | Value | Units |
|--|-----------|--------|----------|------------------|
| Gate-Source Voltage | Vgs | Q1 | 9.0 | V |
| | | Q2 | 9.0 | |
| VIN Voltage | Vvin | | 18.0 | V |
| PH Voltage, DC | Vphase_dc | | 18.0 | V |
| PH Voltage, AC (<10 ns) | Vphase_ac | | 25.0 | V |
| DC Drain-Source Current ($T_j = 150^\circ\text{C}$) | Id | Q1 | 8 | A |
| | | Q2 | 13 | |
| Pulsed Drain-Source Current ⁽²⁾ | Idm | Q1 | 12 | A |
| | | Q2 | 20 | |
| Operating Junction Temperature | Tj | BOTH | -40/+150 | $^\circ\text{C}$ |
| Storage Temperature | Ts | BOTH | -50/+150 | $^\circ\text{C}$ |

Notes:

- 1) These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to conditions greater than Recommended Operating Conditions will affect device reliability.
- 2) Pulse width $\leq 1\text{ms}$, duty cycle $\leq 2\%$.

Thermal Information ^{Note 1}

| Parameter | Symbol | Typ. | | Units |
|--|----------------------|------|------|-------|
| Thermal Resistance Junction to Ambient | $R_{\theta JA}$ | Q1 | 30.1 | °C/W |
| | | Q2 | 31.7 | |
| Thermal Resistance Junction to Top of Package | $R_{\theta JC(TOP)}$ | Q1 | 14.7 | |
| | | Q2 | 15.9 | |
| Thermal Resistance Junction to Board | $R_{\theta JB}$ | Q1 | 6.6 | |
| | | Q2 | 8.3 | |
| Thermal Characterization Parameter - Junction to top | Ψ_{JT} | 0.8 | | |
| Thermal Characterization Parameter - Junction to board | Ψ_{JB} | 8.1 | | |

Notes:

- 1) Simulated on 2S2P board based upon JESD51-5 specifications.

Recommended Operating Conditions

($T_a = 25^\circ\text{C}$ Unless Otherwise Specified.)

| Parameter | Symbol | Conditions | Max. | Units |
|--------------------------------------|-----------|---|----------|-------|
| VIN Operating Voltage ⁽¹⁾ | V_{VIN} | Insure any ringing on PH pins does not exceed Absolute Maximum ratings for PH pins. | 15 | V |
| Gate-Source Operating Voltage | V_{GS} | | 5.5 | V |
| Operating Frequency ⁽²⁾ | F_{SW} | | 2 | MHz |
| Operating Junction Temperature | T_J | | -40/+125 | °C |

Notes:

- 1) Attention to proper VIN supply bypassing and tight PCB layout must be observed to keep the peak voltage of any ringing on the phase node, at the PH pins, below the Absolute Maximum Ratings above.
- 2) The device is very capable of switching at higher frequencies. Contact Silanna with your requirements so we can best ensure the highest reliability for the device in your applications at higher switching frequencies.

Static Electrical Characteristics

(Ta= 25°C Unless Otherwise Specified)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Units | |
|--|--|---|------|------|------|-------|----|
| Gate-Source Leakage Current | I _{gss} | V _{ds} = 0 V, V _{gs} = +5.5 V | | 10 | 100 | nA | |
| | | V _{ds} = 0 V, V _{gs} = -5.5 V | -100 | -10 | | | |
| Gate-Source Threshold Voltage (ext) | V _{th} | V _{gs} = V _{ds} , I _d = 250 μA | Q1 | 0.9 | 1.0 | 1.2 | V |
| | | | Q2 | 0.75 | 1.0 | 1.2 | |
| Drain-Source Breakdown Voltage | B _{vdss} | V _{gs} = 0 V, I _d = 250 μA | Q1 | 25 | | | V |
| | | | Q2 | 25 | | | |
| Drain-Source Leakage Current | I _{dss} | V _{DS} = 12.5 V, V _{GS} =0 | Q1 | | 70 | 1000 | nA |
| | | V _{DS} = 12.5 V, V _{GS} =0 | Q2 | | 120 | 2000 | |
| Drain-Source On-State Resistance (4.5 V) | R _{DS(ON)4.5V} (Notes 1,2) | V _{gs} = 4.5 V, I _d = 8 A | Q1 | | 20 | 27 | mΩ |
| | | V _{gs} = 4.5 V, I _d = 13 A | Q2 | | 8.5 | 11 | |
| Body Diode Forward Voltage | V _{SD} | V _{gs} = 0 V, I _d = 1 A | Q1 | | 0.72 | | V |
| | | | Q2 | | 0.69 | | |

Notes:

- 1) Measured using pulse techniques – pulse width = 300 μs and duty cycle = 1% to minimize junction self-heating.
- 2) Measured using 4-wire (Kelvin) voltage sensing within 0.05" (2 mm) of the drain and source aggregate connections.

Dynamic Electrical Characteristics

(Ta= 25°C Unless Otherwise Specified)

| Parameter | Symbol | Conditions | | Min. | Typ. | Max. | Units |
|---|---------|---|----|------|------|------|-------|
| Gate-Source Input Capacitance | Ciss | Vds = 12.5 V, Vgs = 0 V, f = 1.0 MHz | Q1 | | 240 | 310 | pF |
| | | | Q2 | | 560 | 630 | |
| Drain-Source Output Capacitance | Coss | Vds = 12.5 V, Vgs = 0 V, f = 1.0 MHz | Q1 | | 210 | 280 | pF |
| | | | Q2 | | 500 | 600 | |
| Reverse Transfer (Drain-Gate) Capacitance | Crss | Vds = 12.5 V, Vgs = 0 V, f = 1.0 MHz | Q1 | | 5.5 | | pF |
| | | | Q2 | | 13.0 | | |
| Gate Resistance | Rg | | Q1 | | 0.3 | | Ω |
| | | | Q2 | | 0.5 | | |
| Total Gate Charge (Vgs = 4.5 V) | Qg(4.5) | Vds = 12.5 V, Ids = 8 A | Q1 | | 1.6 | 1.9 | nC |
| | | Vds = 12.5 V, Ids = 13 A | Q2 | | 3.9 | 4.5 | |
| Threshold Gate Charge ⁽¹⁾ | Qg(th) | Vds = 12.5 V, Ids = 8 A | Q1 | | 0.30 | | nC |
| | | Vds = 12.5 V, Ids = 13 A | Q2 | | 0.76 | | |
| Gate-Source Charge | Qgs | Vds = 12.5 V, Ids = 8 A | Q1 | | 0.56 | | nC |
| | | Vds = 12.5 V, Ids = 13 A | Q2 | | 0.86 | | |
| Gate-Drain (Miller) Charge | Qgd | Vds = 12.5 V, Ids = 8 A | Q1 | | 0.16 | | nC |
| | | Vds = 12.5 V, Ids = 13 A | Q2 | | 0.33 | | |
| Output Charge | Qoss | Vds = 12.5 V, Ids = 8 A | Q1 | | 3.1 | | nC |
| | | Vds = 12.5 V, Ids = 13 A | Q2 | | 7.5 | | |

Notes:

- 1) Qg(th) is defined as the gate charge value to the measured value of the gate-source threshold voltage, Vgs(th).

Product Ordering Information

SZPB9317A-BF34 15 V, 8 Amp Half Bridge in a 3.7mm x 4 mm, 0.5 mm lead pitch, 18 lead QFN package.

Product Image

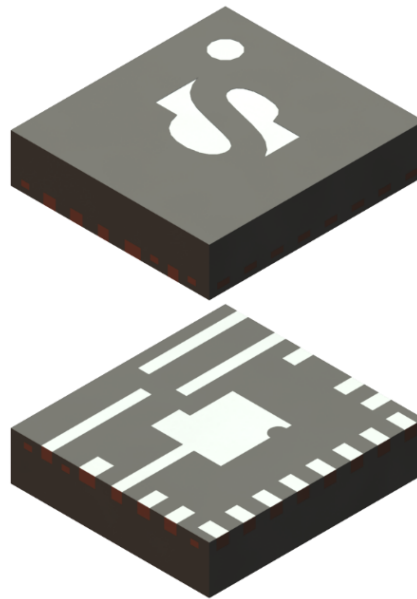
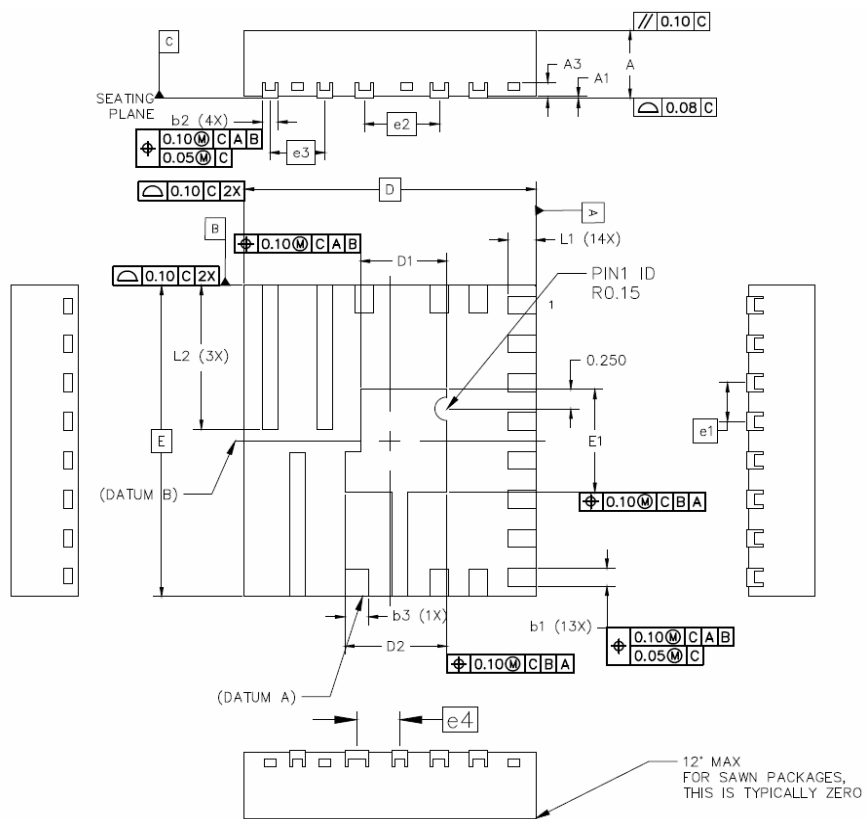


Figure 3: SZPB9317A-B Product Image

Package Dimensions



| DIMENSION TABLE | | | |
|-----------------|-----------|---------|---------|
| SYMBOL | MINIMUM | NOMINAL | MAXIMUM |
| A | 0.80 | 0.90 | 1.00 |
| A1 | 0.00 | 0.02 | 0.05 |
| A3 | 0.203 Ref | | |
| b1 | 0.18 | 0.23 | 0.28 |
| b2 | 0.15 | 0.20 | 0.25 |
| b3 | 0.25 | 0.30 | 0.35 |
| D | 3.70 BSC | | |
| E | 4.00 BSC | | |
| D1 | 1.00 | 1.10 | 1.20 |
| D2 | 1.20 | 1.30 | 1.40 |
| E1 | 1.22 | 1.32 | 1.42 |
| e1 | 0.50 BSC | | |
| e2 | 0.95 BSC | | |
| e3 | 0.70 BSC | | |
| e4 | 0.55 BSC | | |
| L1 | 0.25 | 0.35 | 0.45 |
| L2 | 1.77 | 1.87 | 1.97 |
| N | 18 | | |

- NOTE:
1. Dimensioning and tolerancing conform to ASME Y14.5–2009
 2. All dimensions are in millimeters
 3. N is the total number of terminals
 4. Unilateral coplanarity zone applies to the exposed pas as well as the terminals

Figure 4: F34 Package Dimensions

Recommended PCB Footprint

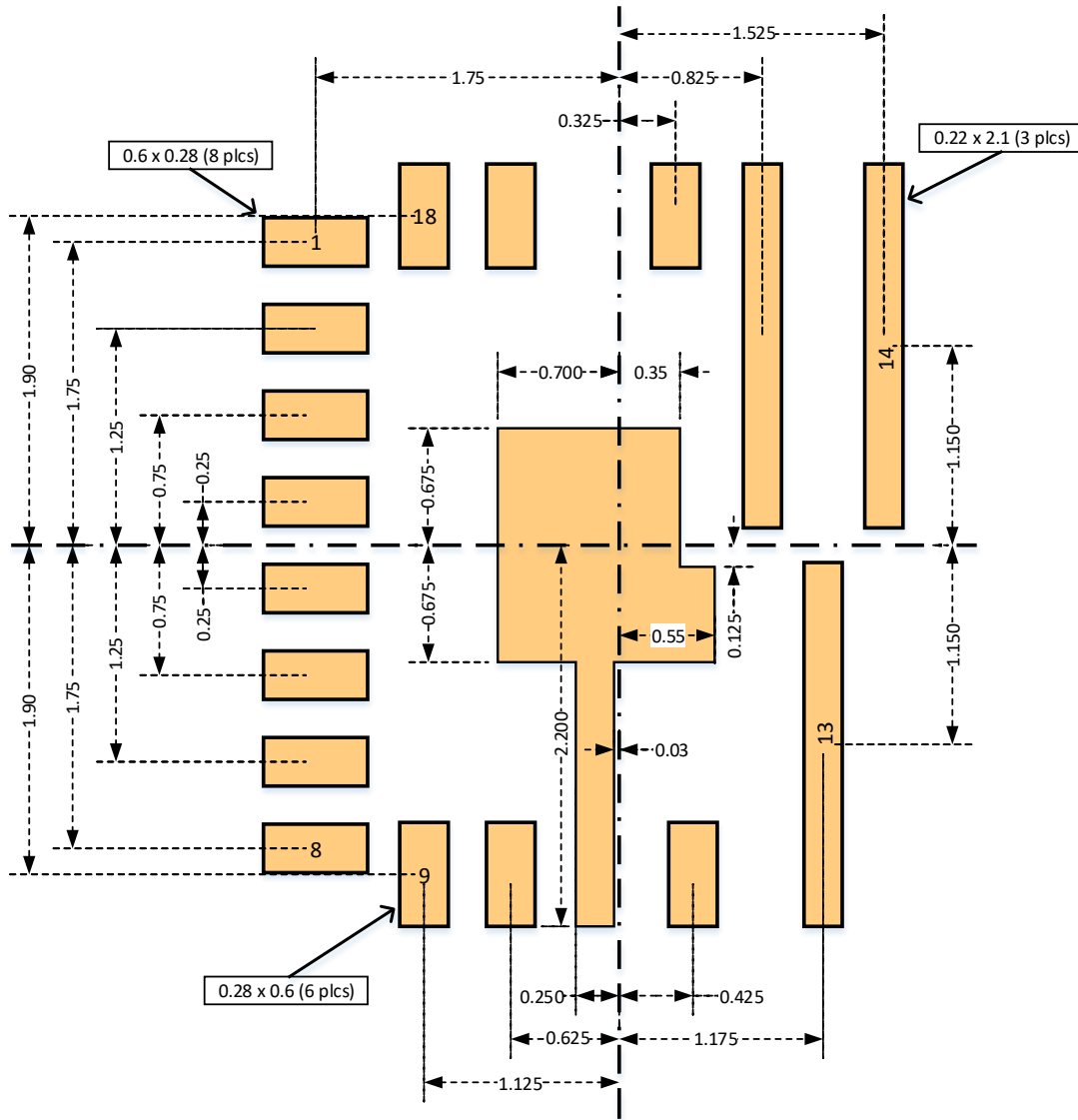


Figure 5: Recommended PCB Footprint

Revision History

| Date | Revision | Notes | Author |
|-----------------|----------|---|--------|
| June 18, 2018 | 1.0 | Initial release | TW |
| August 21, 2018 | 2.0 | Adjusted Thermal Information specs. | TW |
| March 12, 2019 | 3.0 | Final Datasheet release. | TW |
| June 20, 2019 | 4.0 | Update header/footers and add the new logo. | CR |

Silanna Semiconductor Proprietary and Confidential

Information furnished by Silanna Semiconductor is believed to be accurate and reliable. However, no responsibility is assumed for its use. Silanna Semiconductor makes no representation that the interconnection of its circuits as described herein will not infringe on existing patents rights.

4795 Eastgate Mall, Suite 100, San Diego, CA 92121
Toll Free: (888) 637-3564 | Fax: (858) 373-0437 | www.powerdensity.com